

CLAIMS

1. A method of eliminating, using a beam of laser radiation, defects lying within a laminate formed from  
5 at least a first substrate and from at least a second substrate, said laminate incorporating, between said first and second substrates, at least one "smart" active system, **characterized in that** it consists of:
  - a phase of locating at least one defect lying  
10 within the active system; and
  - a phase of ablating the defect, consisting in circumscribing the latter using said laser beam.
2. The method as claimed in claim 1, **characterized in**  
15 **that** the defect is circumscribed using a continuous laser beam.
3. The method as claimed in claim 1, **characterized in**  
20 **that** the defect is circumscribed using a number of laser pulses.
4. The method as claimed in one of claims 1 to 3, **characterized in that** the phase of locating the defect is carried out by optical means, either manually (human  
25 intervention) or automatically using image processing software.
5. The method as claimed in claim 1, **characterized in**  
30 **that** a phase of pinpointing the defect is then carried out using at least a first laser beam pulse.
6. The method as claimed in claim 5, **characterized in**  
**that** the pinpointing phase incorporates an intermediate phase of resetting the laser beam according to the  
35 deviation between one of said first pulses and the defect.

7. The method as claimed in either of claims 1 and 6, **characterized in that** the pinpointing phase is carried out using a low power level of the laser beam.

5 8. The method as claimed in any one of the preceding claims, **characterized in that** ablation of the defect consists in moving the laser beam so as to follow approximately the periphery of the defect.

10 9. The method as claimed in any one of the preceding claims, **characterized in that** the wavelength of the laser beam is adapted so that the beam is, on the one hand, absorbed by the layers forming the active system and, on the other hand, transmitted through the  
15 substrate.

10. The method as claimed in any one of the preceding claims, **characterized in that** ablation of the defect consists in electrically isolating the peripheral  
20 region of the defect relative to the active system that includes the defect.

11. The method as claimed in any one of the preceding claims, **characterized in that** ablation of the defect is  
25 carried out through the first substrate.

12. The method as claimed in any one of claims 1 to 10, **characterized in that** ablation of the defect is carried out through the second substrate.

30 13. Glazing comprising at least one electrochemical device, especially an electrically controllable system of the glazing type with variable optical and/or energy properties, of a photovoltaic device or within an  
35 electroluminescent device, said electrochemical device being inserted between two electrodes positioned on either side, having been repaired by the method as claimed in any one of the preceding claims, **characterized in that** the value of the leakage current

- 15 -

is reduced by a factor of 10 at the core of the  
margination of said glazing.